

O I P E
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U.S. Application No. 10/563,499
APPLICANT(S): Michael HALAMA et al.
TITLE: WAFER INSPECTION DEVICE

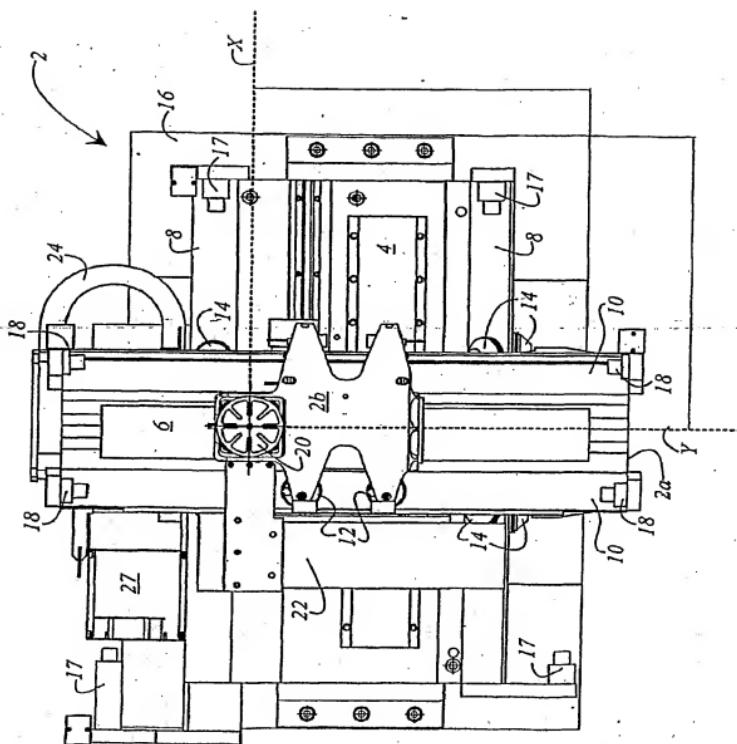
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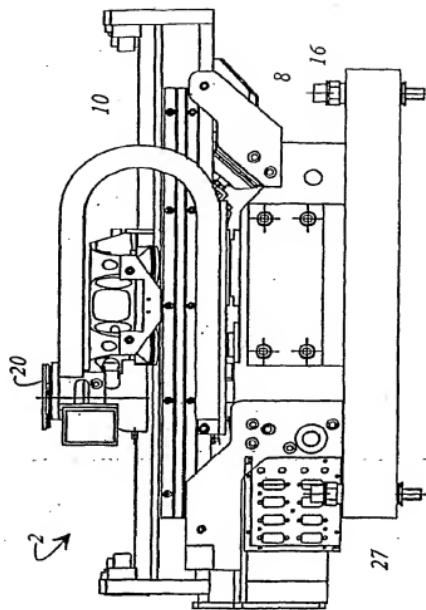
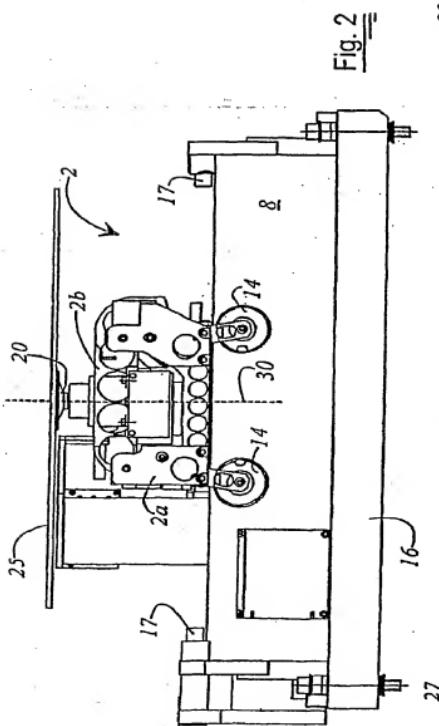
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Fig. 1





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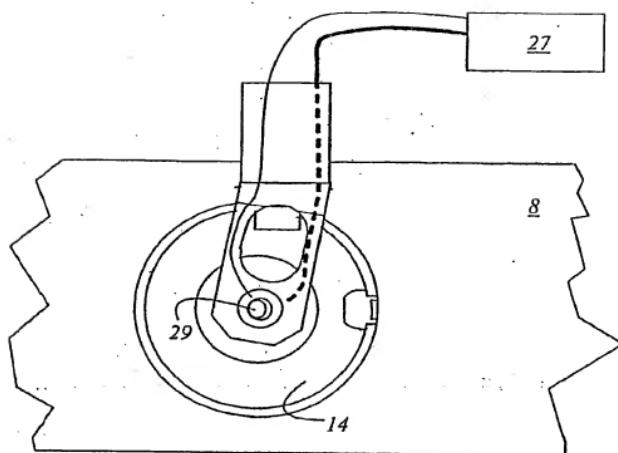


Fig. 4a

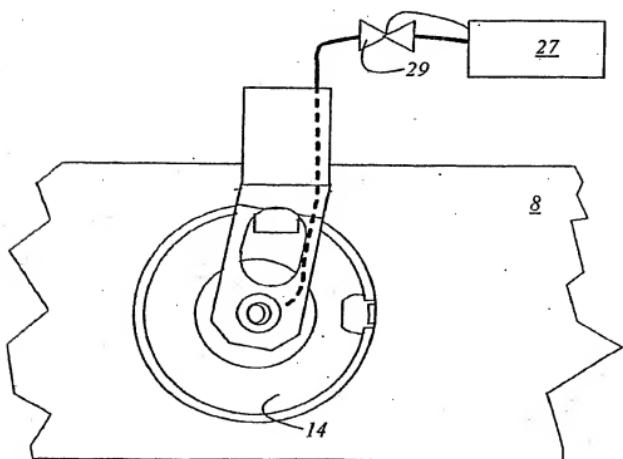


Fig. 4b

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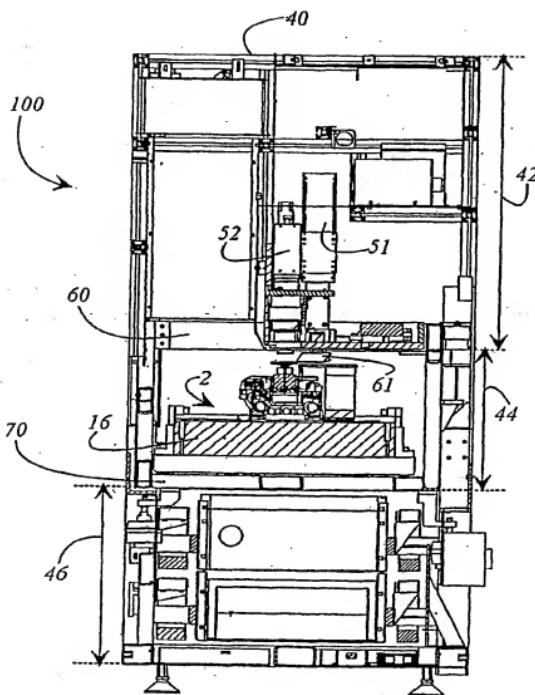


Fig. 5